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## **Geometrical product specification (GPS) — Surface texture: Areal —**

Part 606:

### **Nominal characteristics of non-contact (focus variation) instruments**

*Spécification géométrique des produits (GPS) — État de surface:  
Surfacique —*

*Partie 606: Caractéristiques nominales des instruments sans contact  
(à variation de focale)*



Reference number  
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## Foreword

ISO (the International Organization for Standardization) is a worldwide federation of national standards bodies (ISO member bodies). The work of preparing International Standards is normally carried out through ISO technical committees. Each member body interested in a subject for which a technical committee has been established has the right to be represented on that committee. International organizations, governmental and non-governmental, in liaison with ISO, also take part in the work. ISO collaborates closely with the International Electrotechnical Commission (IEC) on all matters of electrotechnical standardization.

The procedures used to develop this document and those intended for its further maintenance are described in the ISO/IEC Directives, Part 1. In particular the different approval criteria needed for the different types of ISO documents should be noted. This document was drafted in accordance with the editorial rules of the ISO/IEC Directives, Part 2 (see [www.iso.org/directives](http://www.iso.org/directives)).

Attention is drawn to the possibility that some of the elements of this document may be the subject of patent rights. ISO shall not be held responsible for identifying any or all such patent rights. Details of any patent rights identified during the development of the document will be in the Introduction and/or on the ISO list of patent declarations received (see [www.iso.org/patents](http://www.iso.org/patents)).

Any trade name used in this document is information given for the convenience of users and does not constitute an endorsement.

For an explanation on the meaning of ISO specific terms and expressions related to conformity assessment, as well as information about ISO's adherence to the WTO principles in the Technical Barriers to Trade (TBT), see the following URL: [Foreword — Supplementary information](#).

The committee responsible for this document is ISO/TC 213, *Dimensional and geometrical product specifications and verification*.

ISO 25178 consists of the following parts, under the general title *Geometrical product specification (GPS) — Surface texture: Areal*:

- *Part 1: Indication des états de surface*
- *Part 2: Terms, definitions and surface texture parameters*
- *Part 3: Specification operators*
- *Part 6: Classification of methods for measuring surface texture*
- *Part 70: Material measures*
- *Part 71: Software measurement standards*
- *Part 72: Format de fichier XML x3p*
- *Part 601: Nominal characteristics of contact (stylus) instruments*
- *Part 602: Nominal characteristics of non-contact (confocal chromatic probe) instruments*
- *Part 603: Nominal characteristics of non-contact (phase-shifting interferometric microscopy) instruments*
- *Part 604: Nominal characteristics of non-contact (coherence scanning interferometry) instruments*
- *Part 605: Nominal characteristics of non-contact (point autofocus probe) instruments*
- *Part 606: Nominal characteristics of non-contact (focus variation) instruments*
- *Part 701: Calibration and measurement standards for contact (stylus) instruments*

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The following parts are planned:

- *Part 73: Defects on material measures — Terms and definitions*
- *Part 600: Metrological characteristics for areal-topography measuring methods*
- *Part 607: Nominal characteristics of non-contact (imaging confocal microscopy) instruments*

## Introduction

This part of ISO 25178 is a geometrical product specification (GPS) standard and is to be regarded as a general GPS standard (see ISO/TR 14638). It influences the chain link 5 of the chain of standards on areal surface texture.

The ISO/GPS Masterplan given in ISO/TR 14638 gives an overview of the ISO/GPS system of which this part of ISO 25178 is a part of. The fundamental rules of ISO/GPS given in ISO 8015 apply to this part of ISO 25178 and the default decision rules given in ISO 14253-1 apply to specifications made in accordance with this part of ISO 25178, unless otherwise indicated.

For more detailed information of the relation of this part of ISO 25178 to other standards and the GPS matrix model, see [Annex B](#).

This part of ISO 25178 describes the metrological characteristics of focus variation microscopes designed for the measurement of surface topography maps.

For more detailed information on the focus variation technique, see [Annex A](#).

**NOTE** Portions of this part of ISO 25178, particularly the informative sections, describe patented systems and methods. This information is provided only to assist users in understanding the operating principles of focus variation. This part of ISO 25178 is not intended to establish priority for any intellectual property, nor does it imply a license to proprietary technologies described herein.